

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	2078	charge near2 gain	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:03
S3	14	(charge near2 gain) with fail\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:05
S5	0	S3 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:05
S6	41	charge with gain with fail\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:05
S7	1	S6 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:09
S8	11328	stress\$4 with memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:16
S9	488	S8 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:18
S10	31	S8 and ((gray grey) near2 code)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:09

## EAST Search History

S11	289	S8 and (transition\$4 same bits)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/08 13:52
S12	98	S8 and (transition\$4 same bits same address)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:17
S13	0	S12 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:17
S14	6	S11 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:19
S15	372	S8 and (transition\$4 same cycl\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:19
S16	28	S15 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:18
S17	85	S8 and (transition\$4 same cycl\$4 same address)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:20
S18	1	S17 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:22

## EAST Search History

S19	10557	charge with gain	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:20
S20	0	S17 and S19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:20
S21	66	S17 and flash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:23
S22	120	cycl\$4 same address same stress\$4 same memory	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:22
S23	1	S22 and (gray grey)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:22
S24	33	S22 and flash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:32
S25	46	stress\$4 with address with cycl\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:36
S26	7	stress\$4 with address with cycl\$4 with bit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:33

## EAST Search History

S27	339	stress\$4 with cycl\$4 with pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:43
S28	43	S27 and flash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:37
S29	30	stress\$4 with address with pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:41
S30	68	( "4267583"   "4487705"   "4553225"   "4560959"   "4701886"   "4715034"   "4744061"   "4855688"   "4858190"   "4871963"   "4879688"   "4882702"   "4916700"   "4918378"   "4969121"   "5006787"   "5034923"   "5138619"   "5173906"   "5185722"   "5198758"   "5199034"   "5265054"   "5265100"   "5285419"   "5289475"   "5295102"   "5300840"   "5341382"   "5355340"   "5381277"   "5392005"   "5396464"   "5404331"   "5407276"   "5408435"   "5424601"   "5424988"   "5428319"   "5441011"   "5446954"   "5455542"   "5459436"   "5459733"   "5467358"   "5471428"   "5471482"   "5473284"   "5473289"   "5481229"   "5488333"   "5499600"   "5500509"   "5525936"   "5530408"   "5533196"   "5543761"   "5548252"   "5557968"   "5568084"   "5574408"   "5603570"   "5604467"   "5604468"   "5607236"   "5608359").PN. OR ("5883844"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/06/06 18:39
S31	1012	cycl\$4 with address with pattern	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:42

## EAST Search History

S32	4	(cycl\$4 with address with pattern) and (stress\$4 with memory)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:42
S33	242	cycl\$4 with address with pattern with bit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:43
S34	0	cycl\$4 with address with pattern with stress\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:43
S36	31	S27 and ("365" "711" "714").clas.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/06 18:44
S37	8672	(711/103,218 365/230.03,230.06 714/702,718).ccls.	USPAT	OR	ON	2007/06/08 13:58
S38	18	S37 and (charge with gain)	USPAT	OR	ON	2007/06/08 13:58

# EAST Search History *Interference*

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L5	2262	(711/103,218 365/230.03,230.06 714/702,718).ccls.	US-PGPUB	OR	ON	2007/06/08 14:09
L6	278	(charge with gain).clm.	US-PGPUB	OR	ON	2007/06/08 14:10
L7	0	L5 and L6	US-PGPUB	OR	ON	2007/06/08 14:10
L8	138	(charge with fail\$4).clm.	US-PGPUB	OR	ON	2007/06/08 14:10
L9	1	L5 and L8	US-PGPUB	OR	ON	2007/06/08 14:10
L10	55	(gain with fail\$4).clm.	US-PGPUB	OR	ON	2007/06/08 14:10
L11	0	L5 and L10	US-PGPUB	OR	ON	2007/06/08 14:11
L12	137	(stress\$4 near2 signal).clm.	US-PGPUB	OR	ON	2007/06/08 14:11
L13	0	L5 and L12	US-PGPUB	OR	ON	2007/06/08 14:11
L14	624	(cycl\$4 near5 address).clm.	US-PGPUB	OR	ON	2007/06/08 14:11
L15	38	L5 and L14	US-PGPUB	OR	ON	2007/06/08 14:11
L16	402	(cycl\$4 near3 address).clm.	US-PGPUB	OR	ON	2007/06/08 14:11
L17	18	L5 and L16	US-PGPUB	OR	ON	2007/06/08 14:11

[Web](#) [Images](#) [Video](#) [News](#) [Maps](#) [Gmail](#) [more ▾](#)

[Sign in](#)

Google

charge gain failure

Search

[Advanced Search](#)  
[Preferences](#)

Web

Results 1 - 10 of about 1,640,000 for **charge gain failure**. (0.17 seconds)

### Circuit for detecting both **charge gain** and **charge loss** properties ...

This unintentional **charge gain** or **charge loss** can change the memory state of the cell and become a cause of reliability **failure** in the Flash memory array. ...

[www.patentstorm.us/patents/5912836-description.html](http://www.patentstorm.us/patents/5912836-description.html) - 39k - [Cached](#) - [Similar pages](#)

### **Charge gain** stress test circuit for nonvolatile memory and test ...

A **charge gain** stress test circuit for a nonvolatile memory and a test method using the same ... <- Previous Patent (PCB adapter for IC chip **failure** ana. ...

[www.freepatentsonline.com/6323671.html](http://www.freepatentsonline.com/6323671.html) - 29k - [Cached](#) - [Similar pages](#)

### HB 378 - As Introduced - **Failure** to disperse - increase penalty

**Gain**, possibly exceeding minimal in some jurisdictions ... Disorderly conduct is a more common **charge** than **failure** to disperse, however, it is usually used ...

[www.lbo.state.oh.us/fiscal/fiscalnotes/124ga/HB0378IN.HTM](http://www.lbo.state.oh.us/fiscal/fiscalnotes/124ga/HB0378IN.HTM) - 38k - [Cached](#) - [Similar pages](#)

### Turbo **charge** lighttpd with Linux AIO - **Gain** more performance ...

... you have achieved half your success; if you don't, you have achieved half your **failure**. ...

Turbo **charge** lighttpd with Linux AIO - **Gain** more performance ...

[www.cyberciti.biz/tips/howto-increase-lighttpd-performance-with-linux-aio.html](http://www.cyberciti.biz/tips/howto-increase-lighttpd-performance-with-linux-aio.html) - 26k -

[Cached](#) - [Similar pages](#)

### ScienceDirect - Journal of Electrostatics : Electrostatic ...

Electrostatic discharge **failure** mechanism for cordless phone **charge** contacts\*1 ... we hope to **gain** a better understanding of the mechanism responsible for ...

[linkinghub.elsevier.com/retrieve/pii/S030438860000022X](http://linkinghub.elsevier.com/retrieve/pii/S030438860000022X) - [Similar pages](#)

#### [PDF] Recent developments on Flash memory reliability

File Format: PDF/Adobe Acrobat

(a) and **charge gain** from the erased state (b). The corresponding band structures are also depicted. 3. Cell **failure** mechanisms ...

[linkinghub.elsevier.com/retrieve/pii/S0167931705002248](http://linkinghub.elsevier.com/retrieve/pii/S0167931705002248) - [Similar pages](#)

[ [More results from linkinghub.elsevier.com](#) ]

### » How to **gain** competitive advantage from IT | Paul Murphy | ZDNet.com

How to **gain** competitive advantage from IT ... getting the match wrong guarantees **failure**, but putting people with the right backgrounds in **charge** of systems ...

[blogs.zdnet.com/Murphy/?p=600](http://blogs.zdnet.com/Murphy/?p=600) - 51k - [Cached](#) - [Similar pages](#)

### [PDF] An scr-switched, high voltage, high **gain** linear transformer system ...

File Format: PDF/Adobe Acrobat

in the primary drivers. Such graceful **failure** could be an important feature in high reliability systems. **Charge** voltage with. 4. drivers charging a 32 nF ...

[ieeexplore.ieee.org/iel5/6205/16575/00767599.pdf](http://ieeexplore.ieee.org/iel5/6205/16575/00767599.pdf) - [Similar pages](#)

### [PDF] 19.0 Safety and Fault Analyses Postulation of Safety Issues ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)

Quick **charge** of LN2 with warm cryostat. Accident. Fire. Seismic. **Failure** of .... is fire retardant, and will limit heat **gain** and resulting pressurization ...

[noyac3.psfc.mit.edu/bnlpulsed/safety.pdf](http://noyac3.psfc.mit.edu/bnlpulsed/safety.pdf) - [Similar pages](#)

**Reid makes abrupt ministry reshuffle in bid to **gain** control ...**

But Dr Reid took the decision to put him in **charge** of immigration at the ... the Shadow

Home Secretary said: "This is clearly an admission of **failure** on the ...

findarticles.com/p/articles/mi\_qn4158/is\_20060523/ai\_n16411601 - 32k -

Cached - Similar pages

[1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) **[Next](#)**

---

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

---

©2007 Google - [Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)